

Figure 2

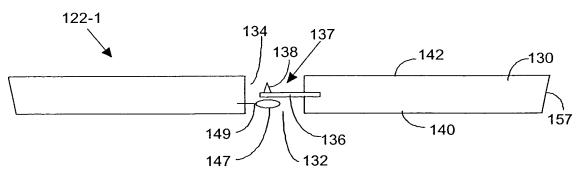
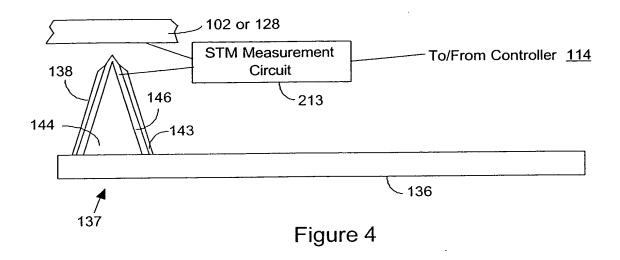


Figure 3



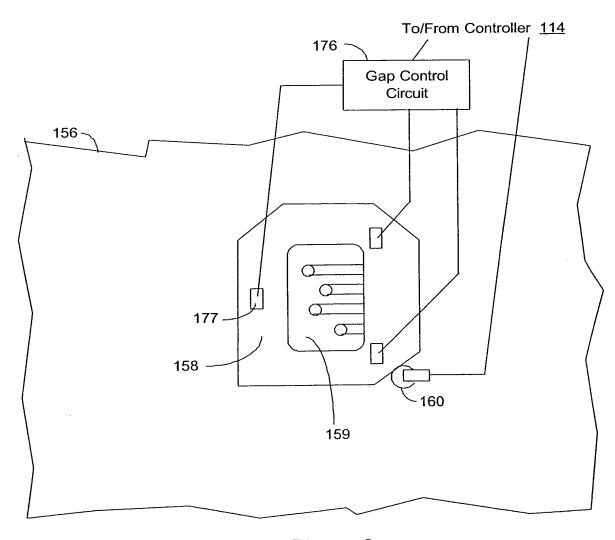
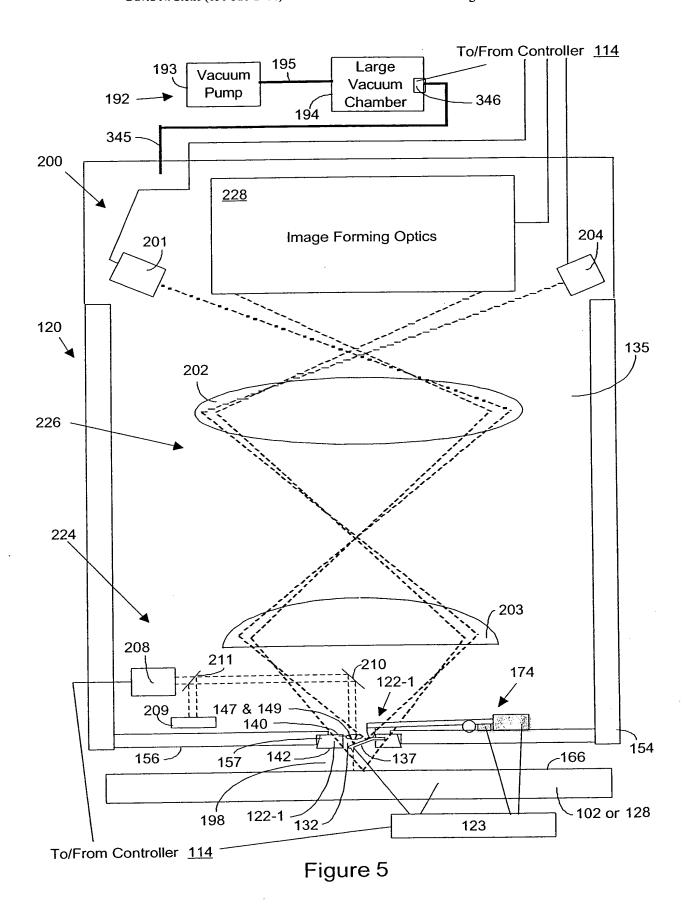


Figure 6



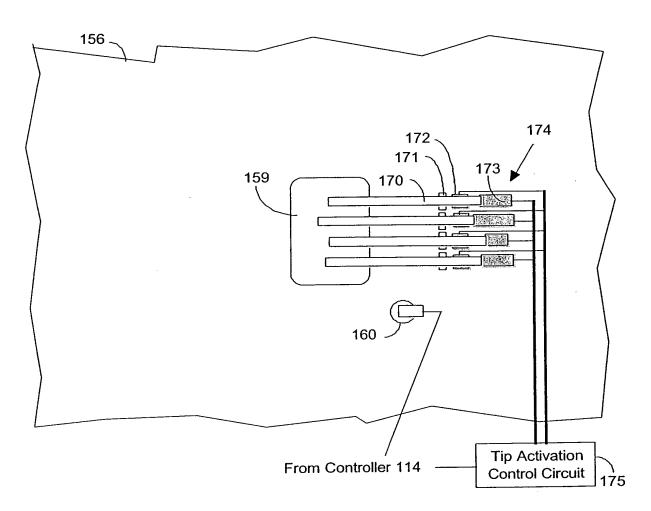


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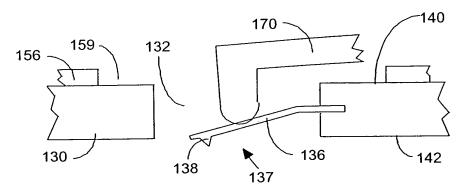


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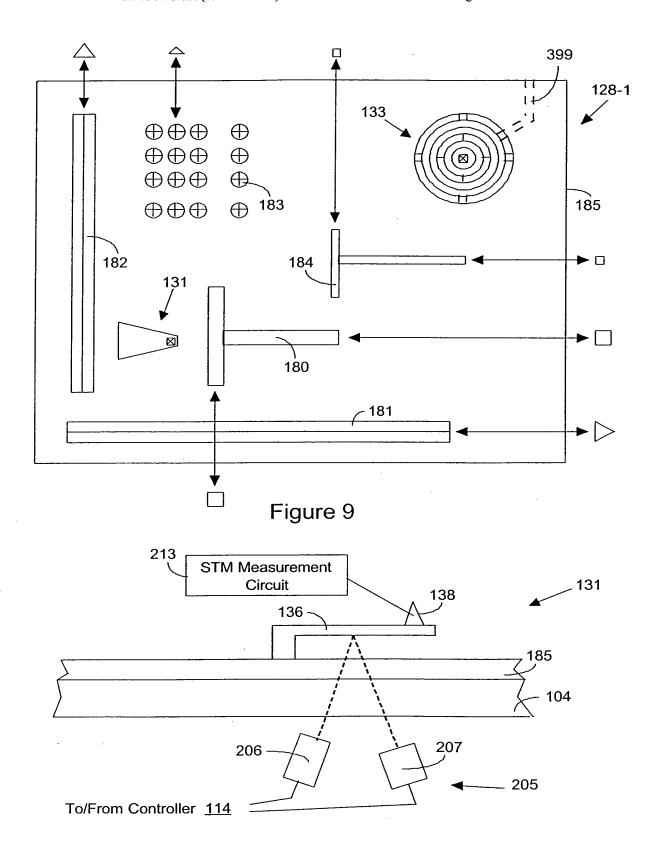


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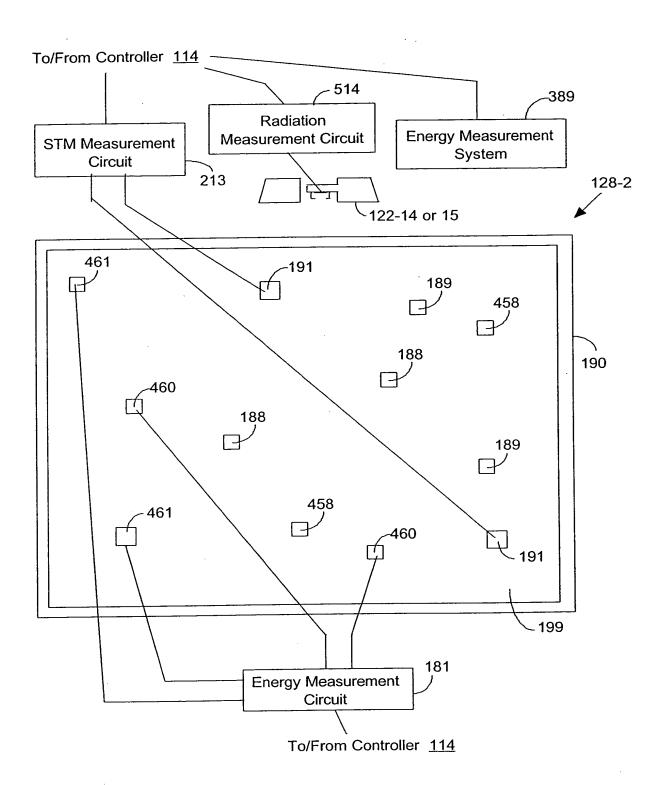
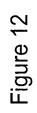
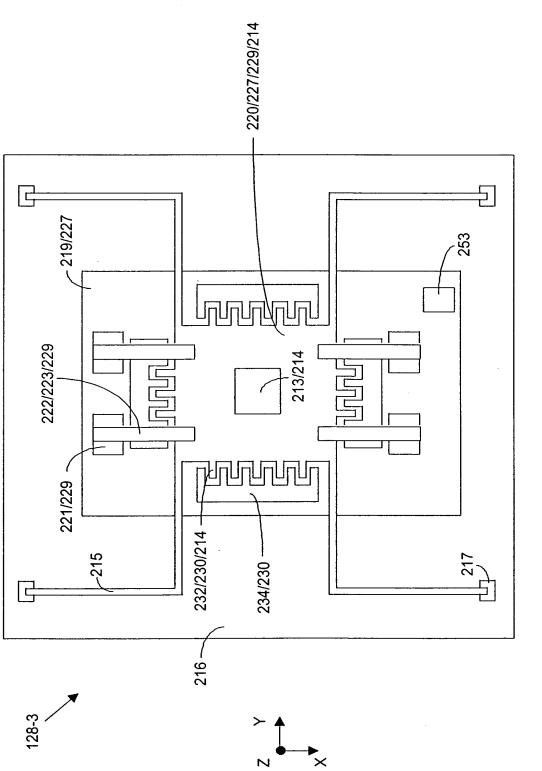


Figure 11





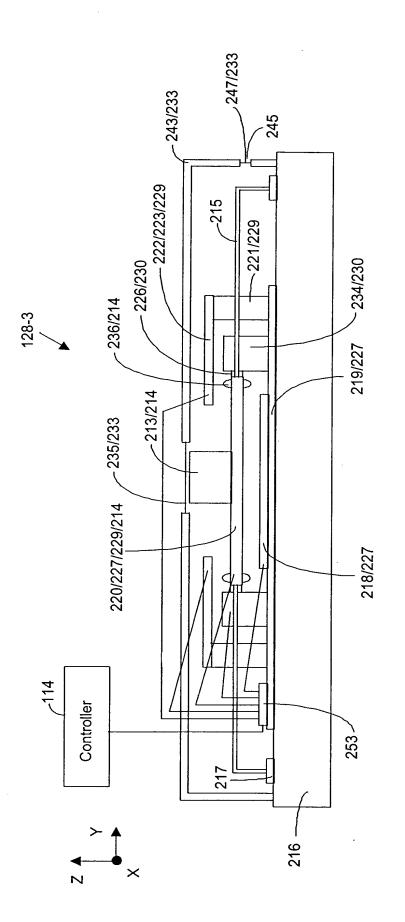
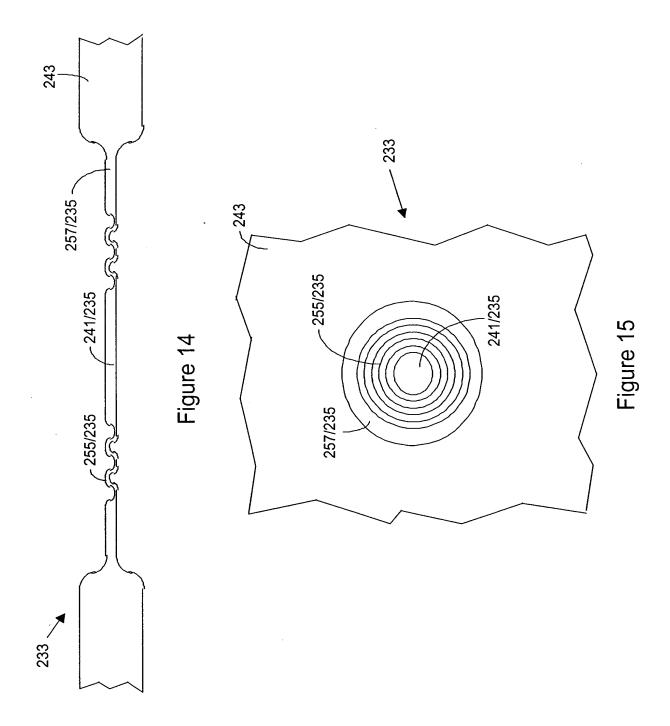


Figure 13

Title: Scanning Probe Microscopy Inspection and Modification System
Inventor: Victor B. Kley App. No. ; Filed:
David N. Slone (650-326-2400) Docket No. 020921-001612US Page 10 of 55



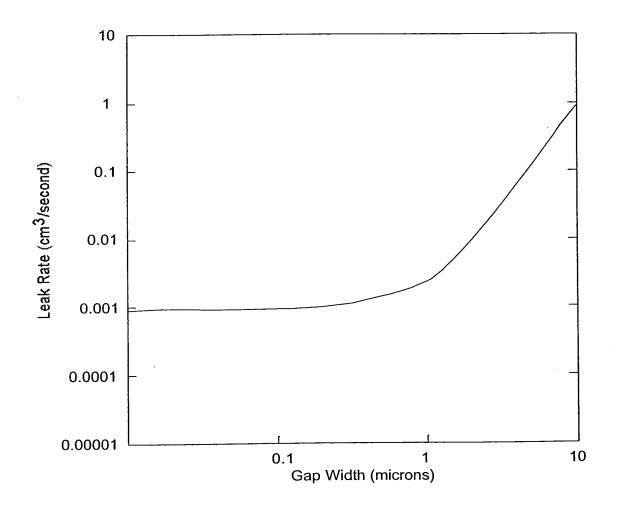


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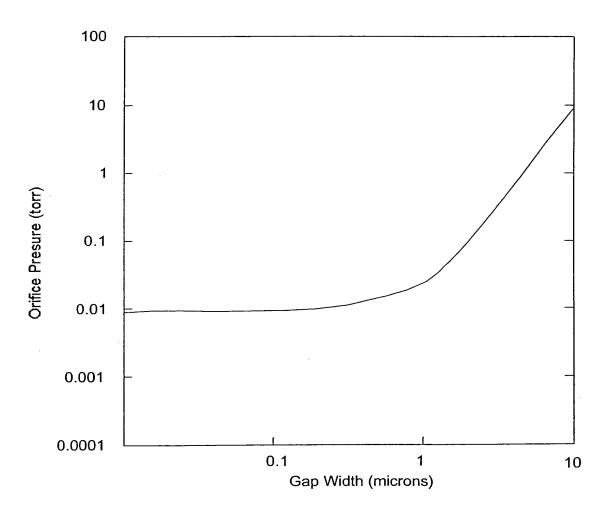


Figure 17

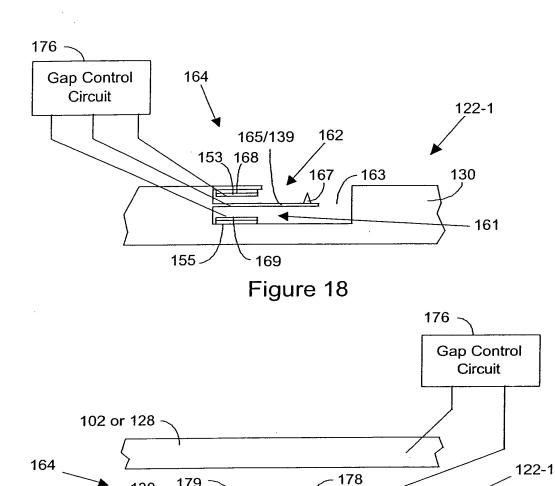


Figure 19

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130

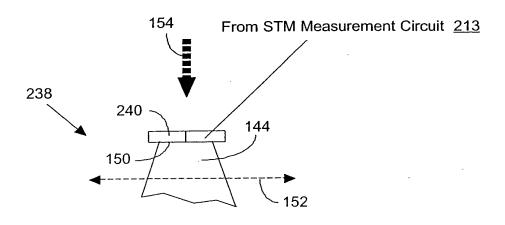


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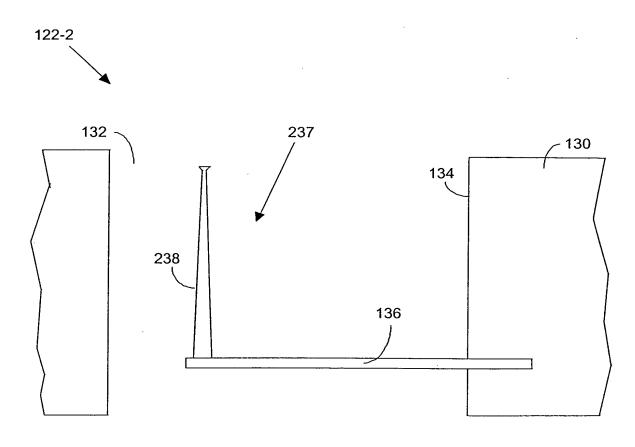


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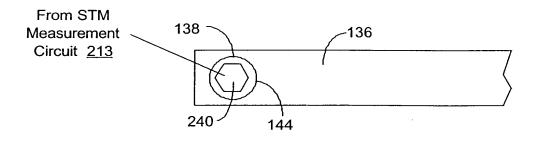
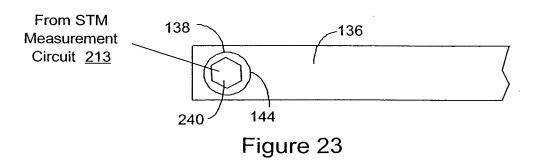


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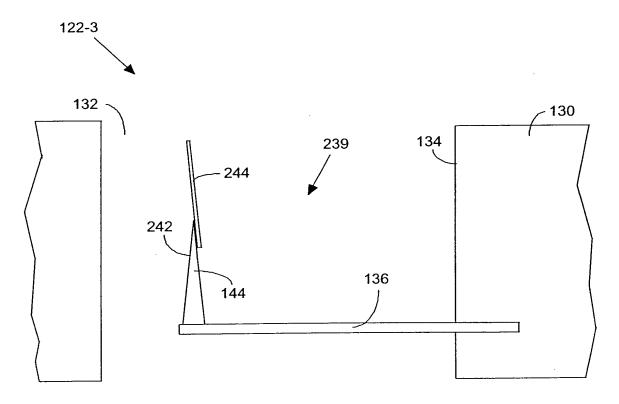


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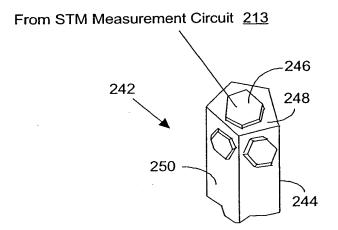


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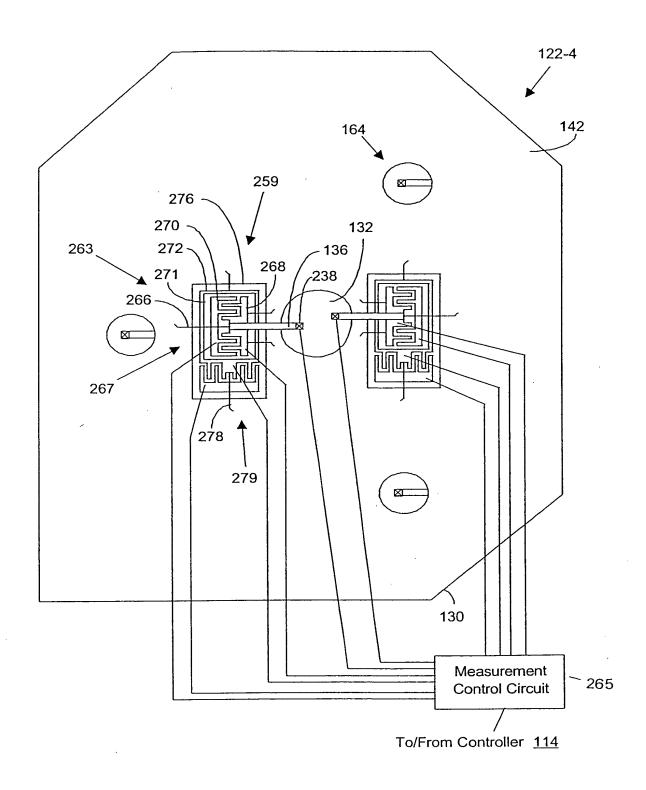
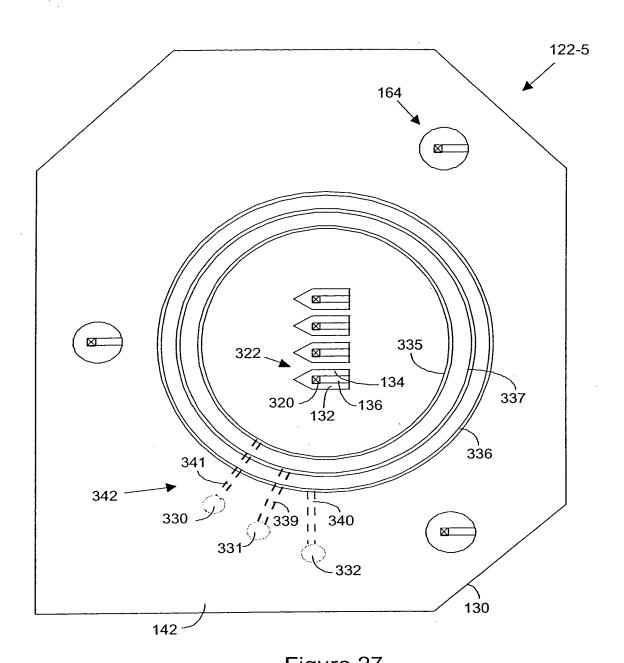


Figure 26



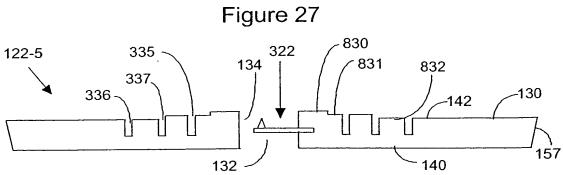


Figure 86

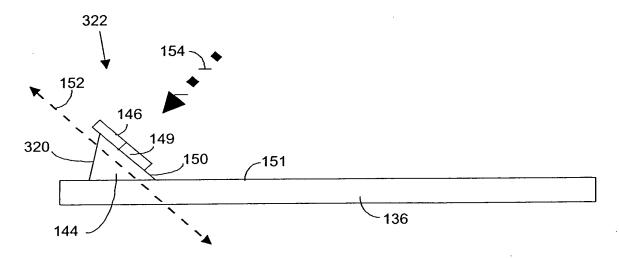


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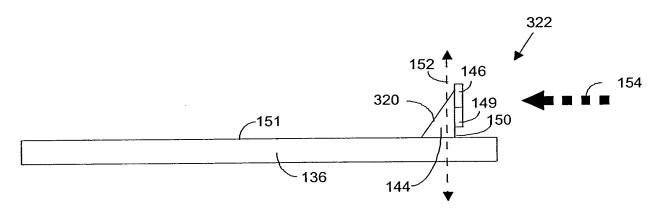
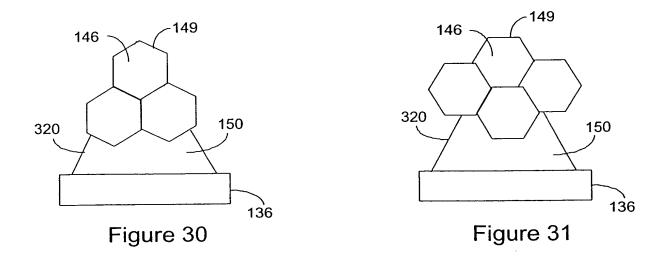


Figure 29



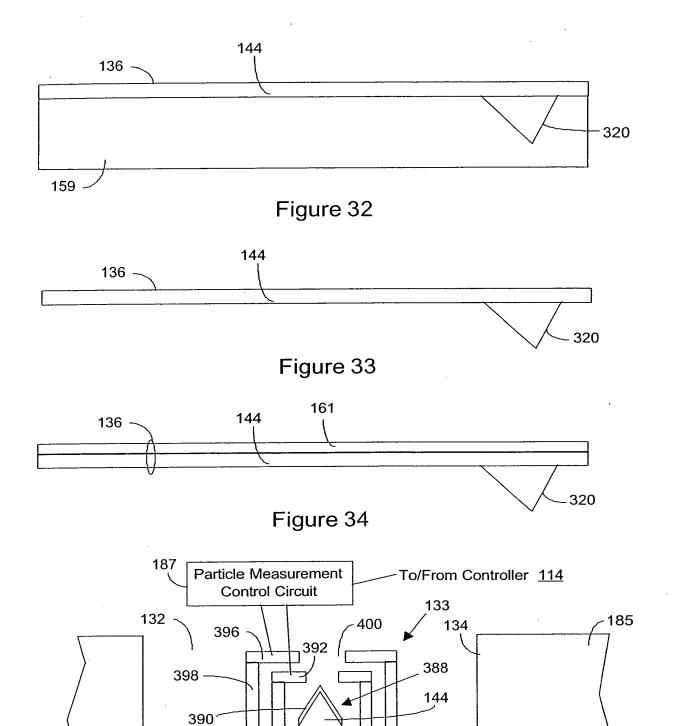


Figure 87

399

386

383

Title: Scanning Probe Microscopy Inspection and Modification System
Inventor: Victor B. Kley App. No. ; Filed:
David N. Slone (650-326-2400) Docket No. 020921-001612US Page 20 of 55

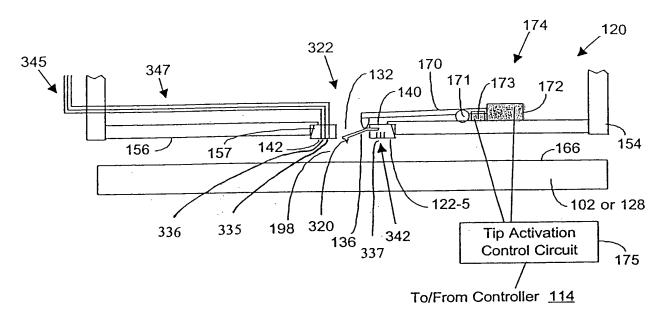
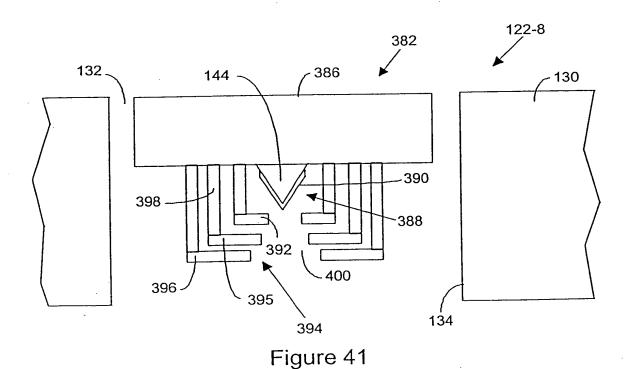


Figure 35



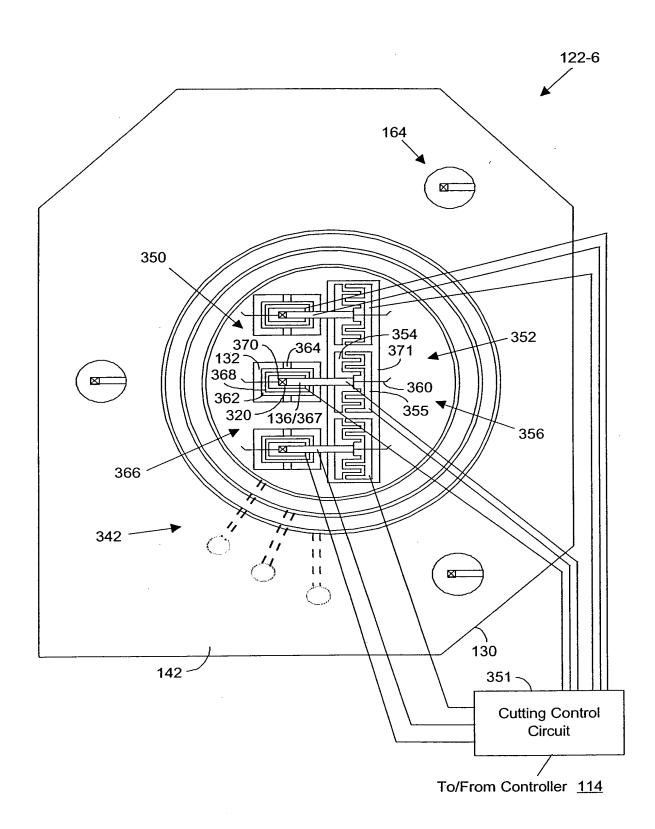


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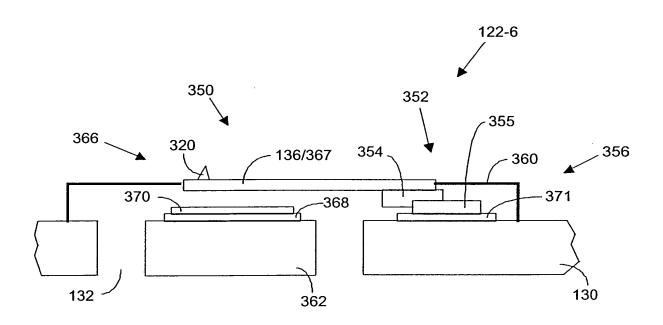


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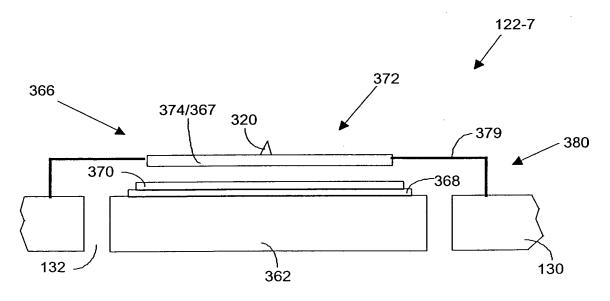


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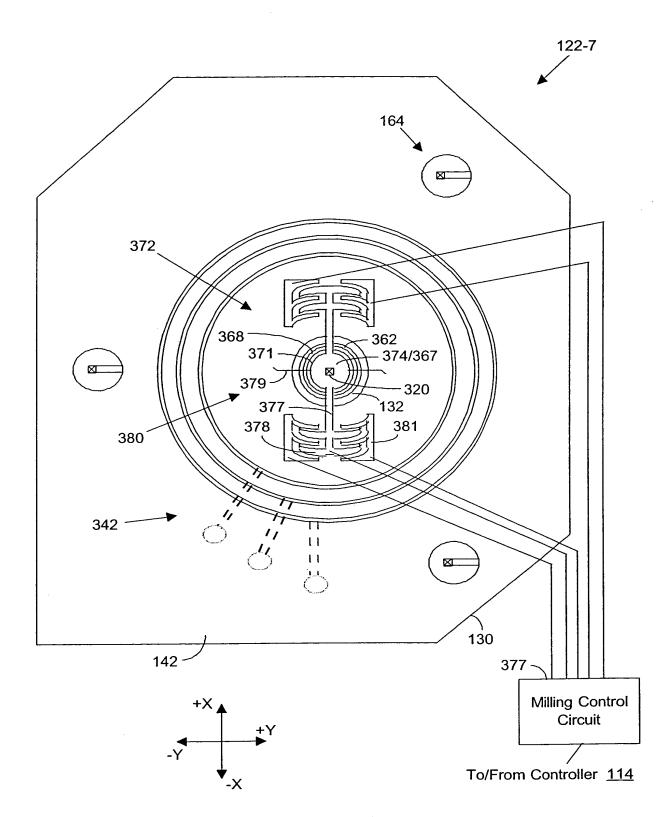


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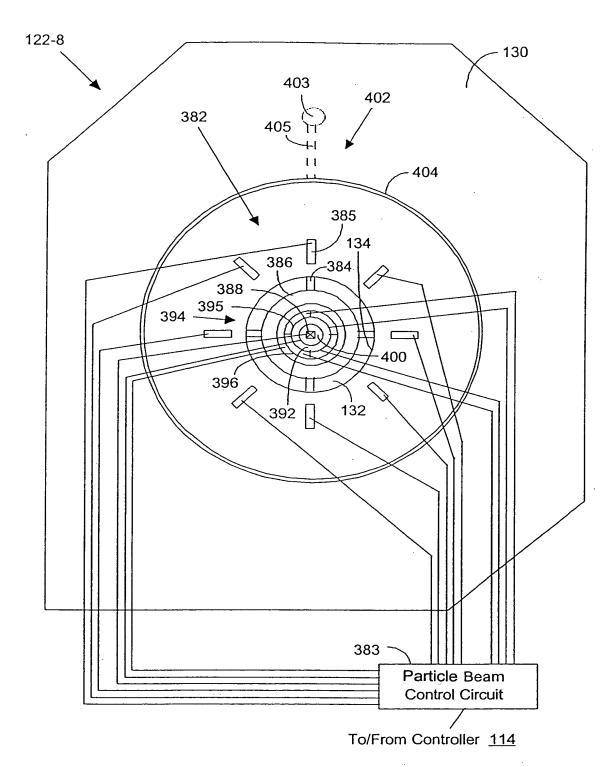


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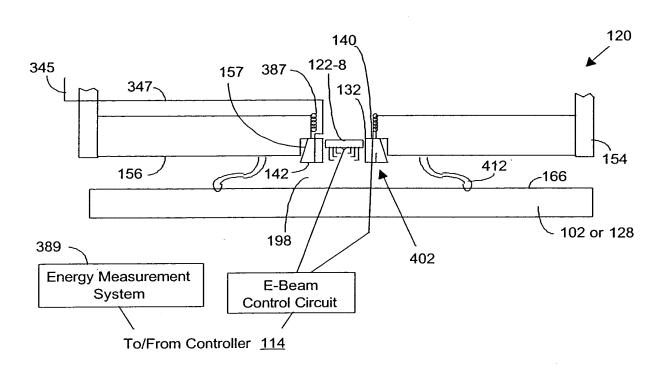


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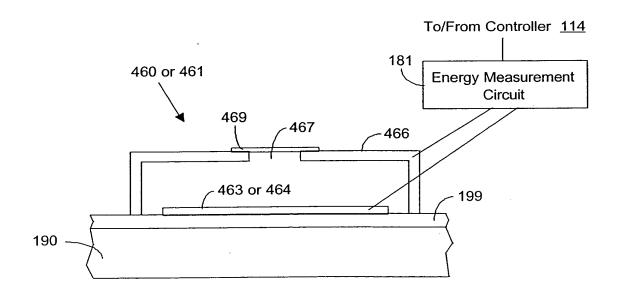


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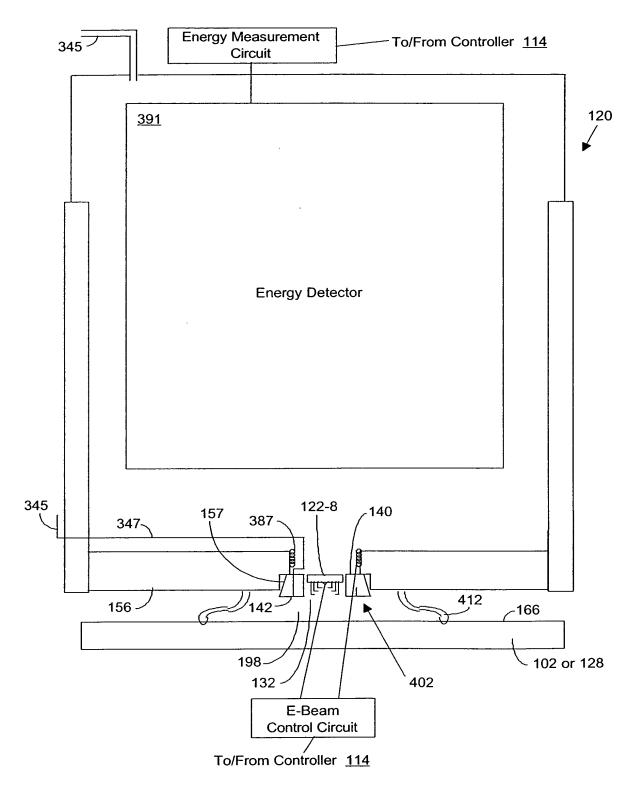


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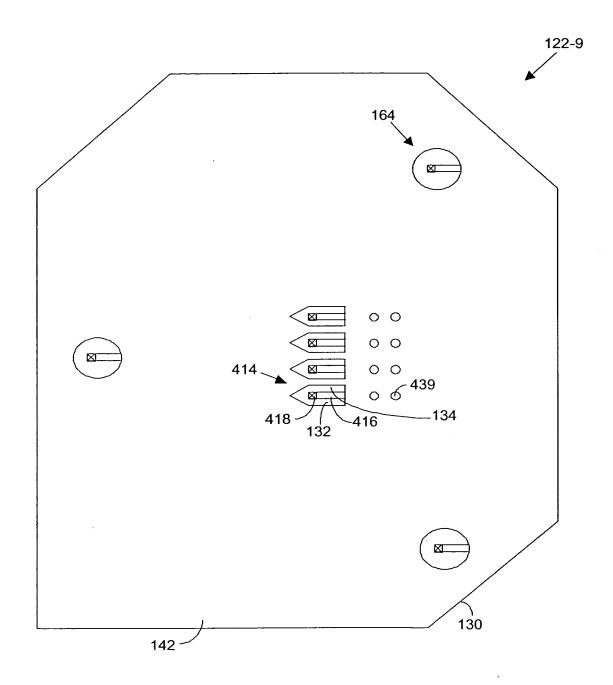


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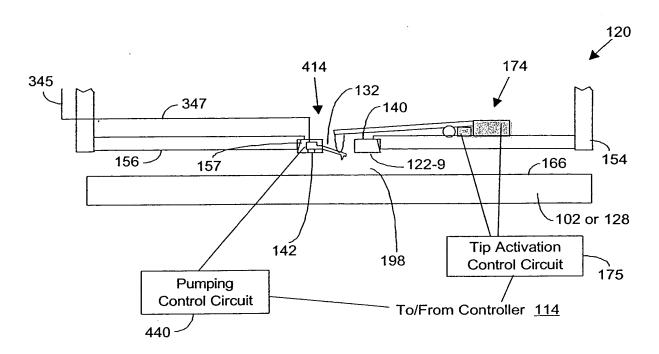
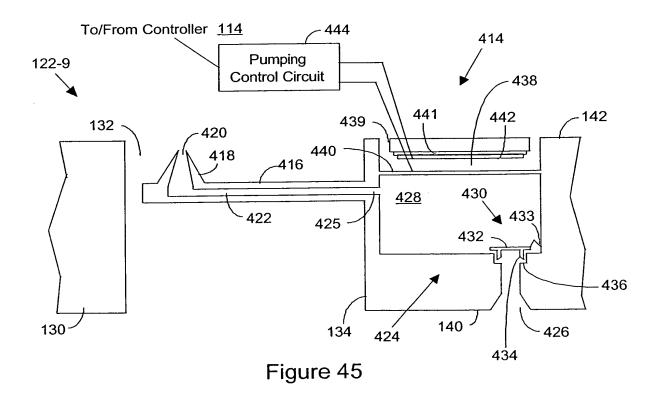


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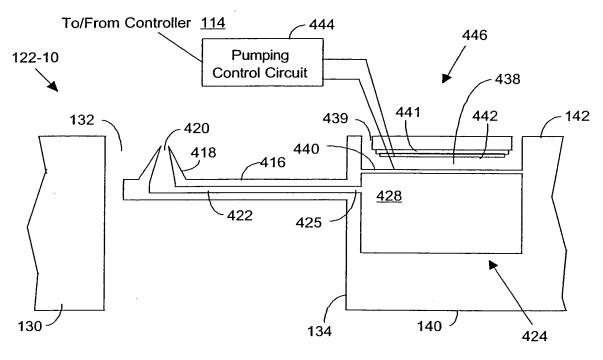


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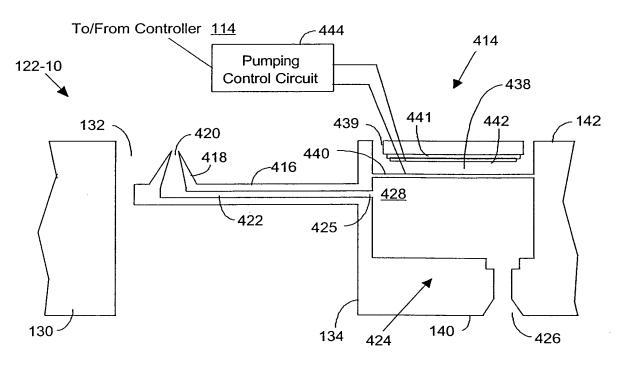


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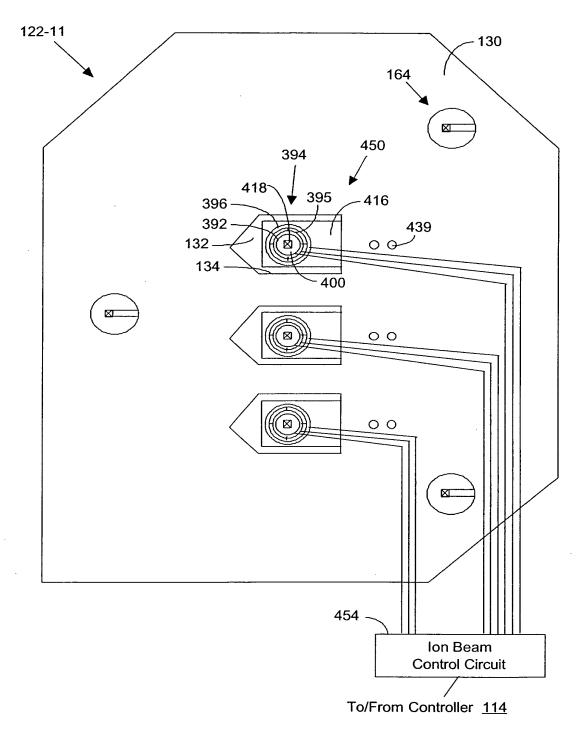


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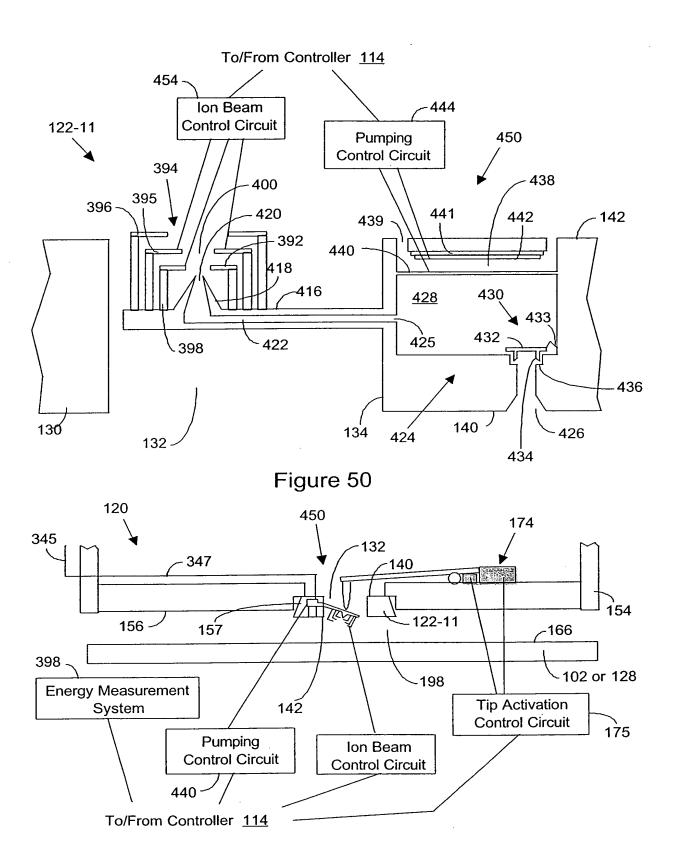


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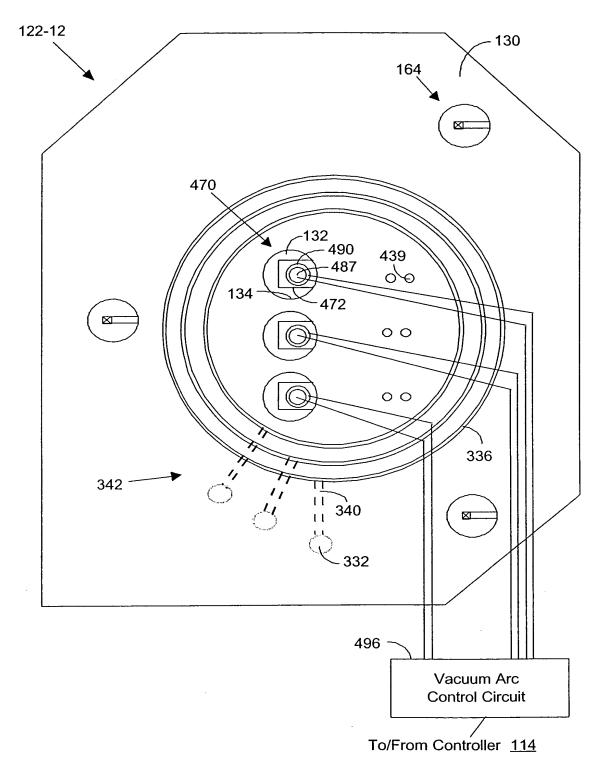


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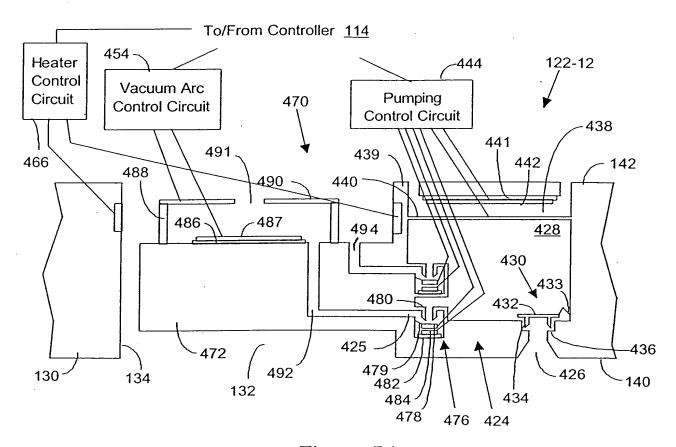


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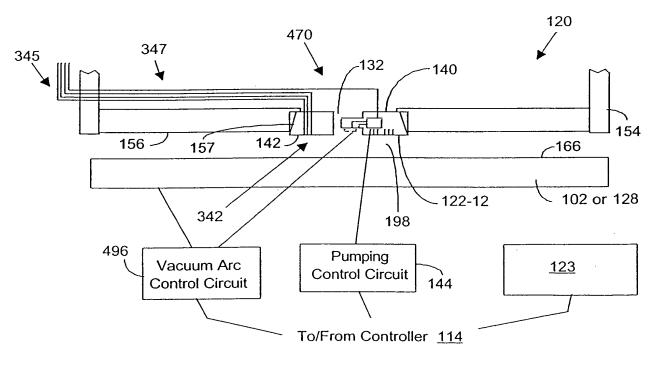


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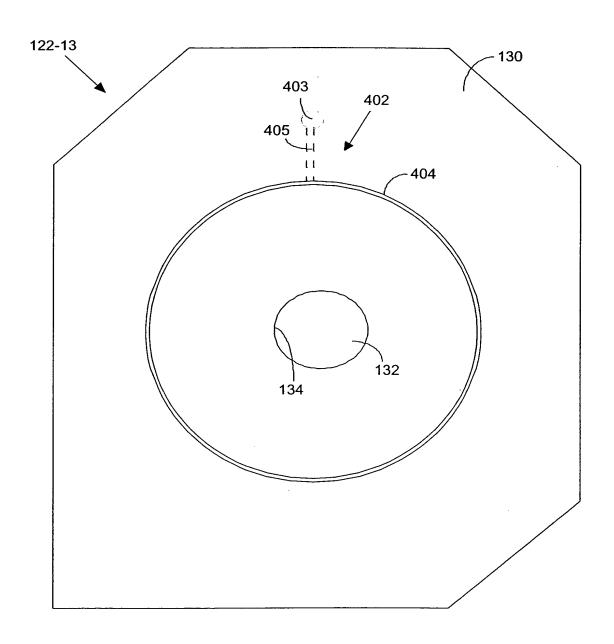


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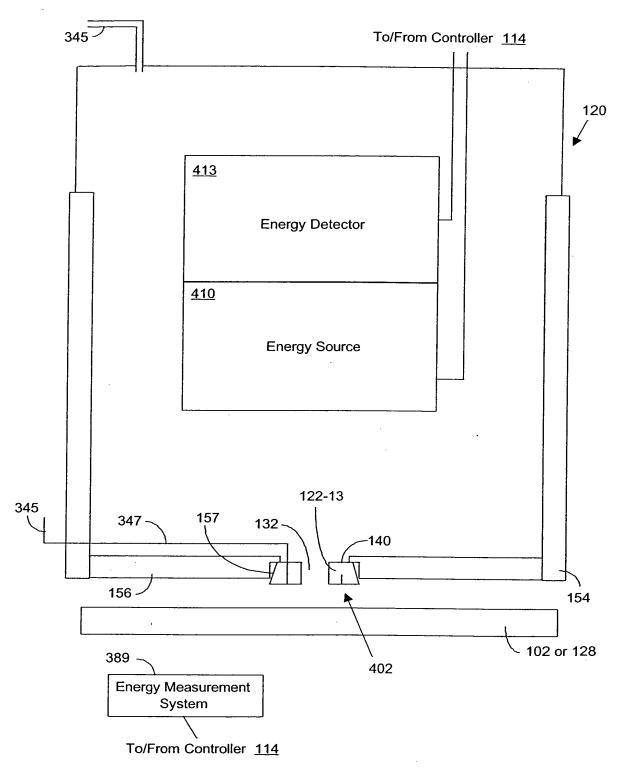


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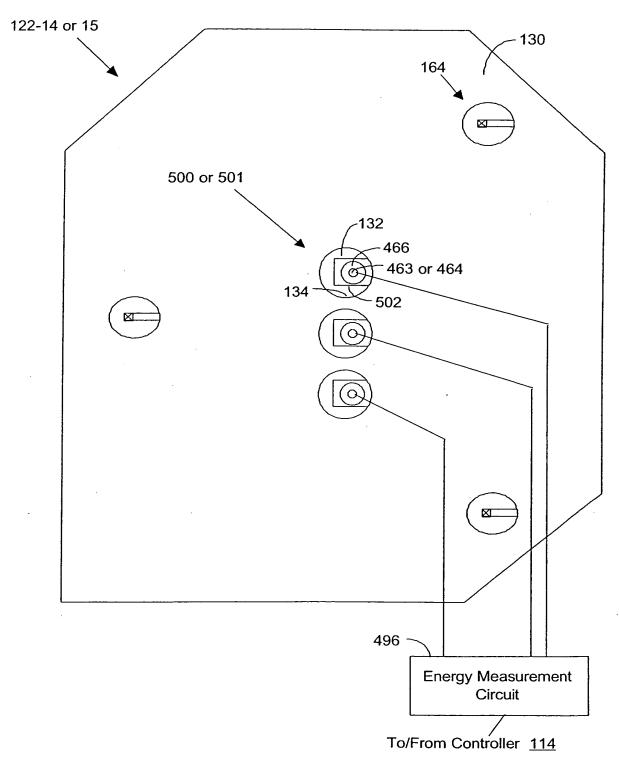


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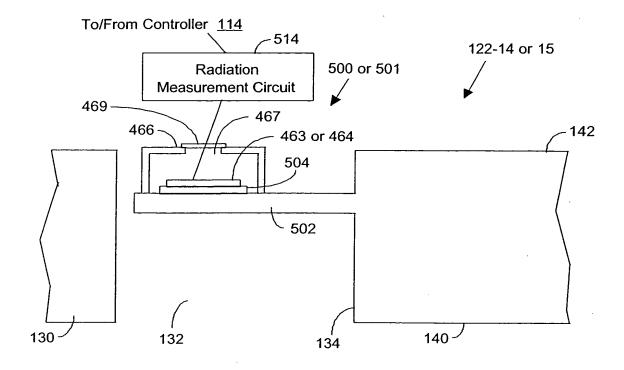


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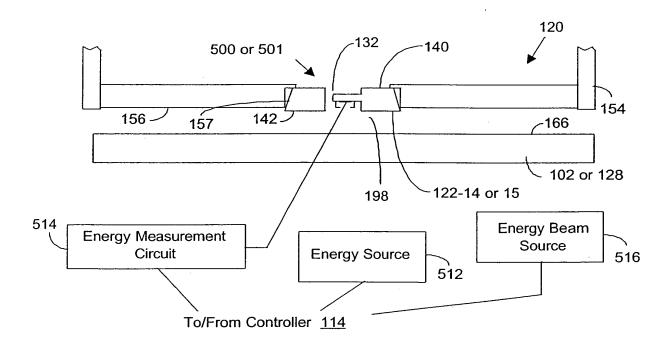


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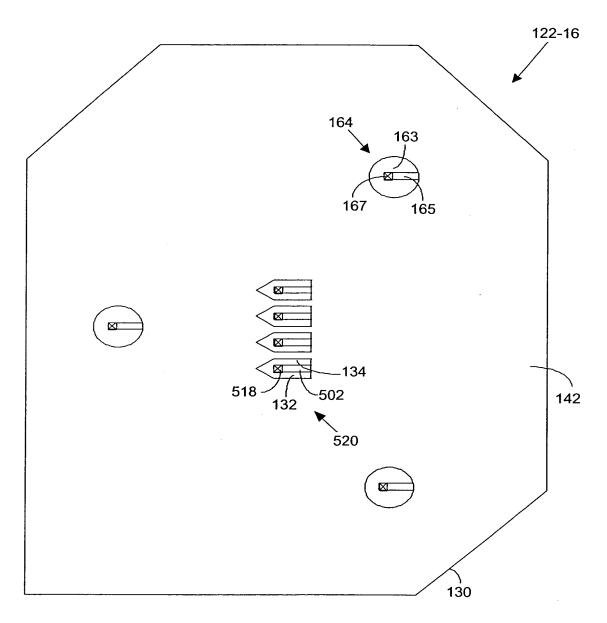


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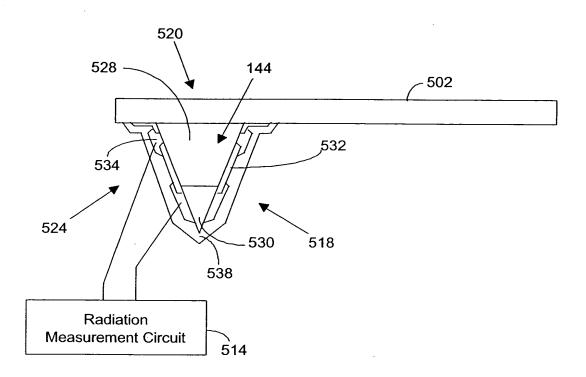


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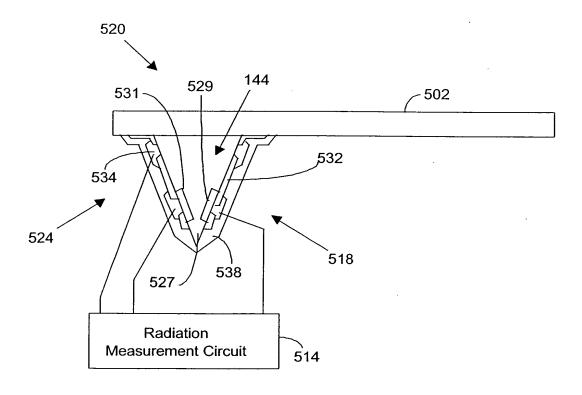


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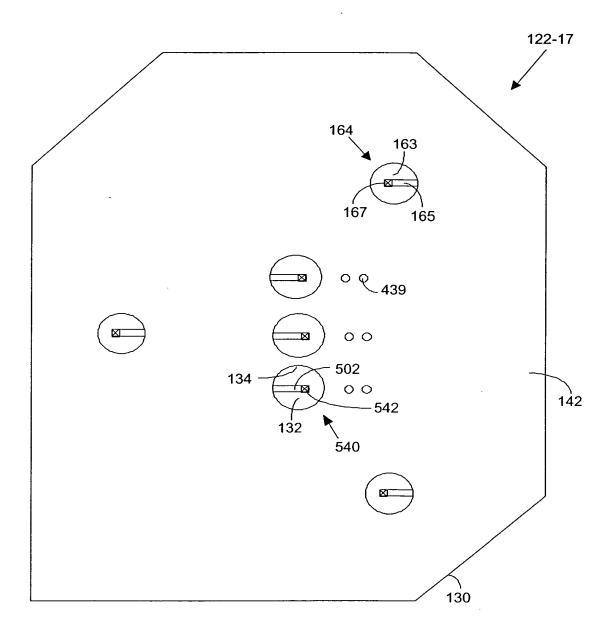


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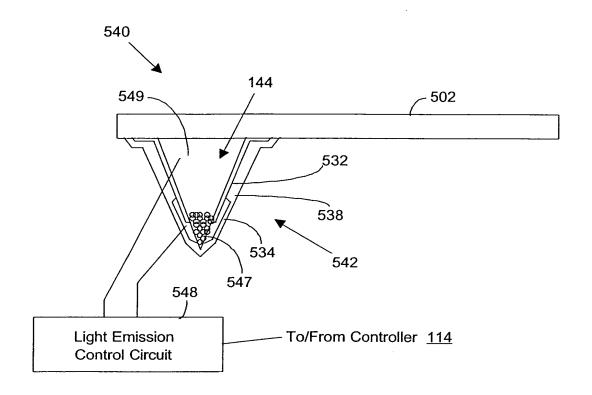


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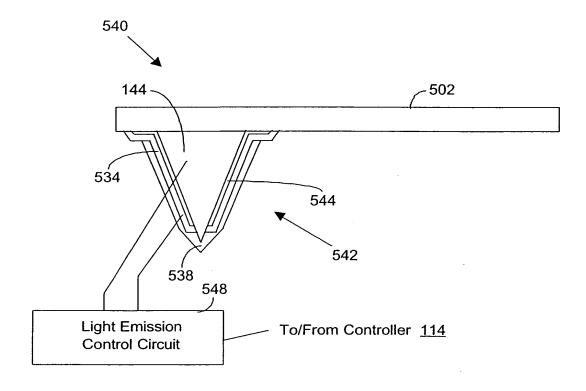


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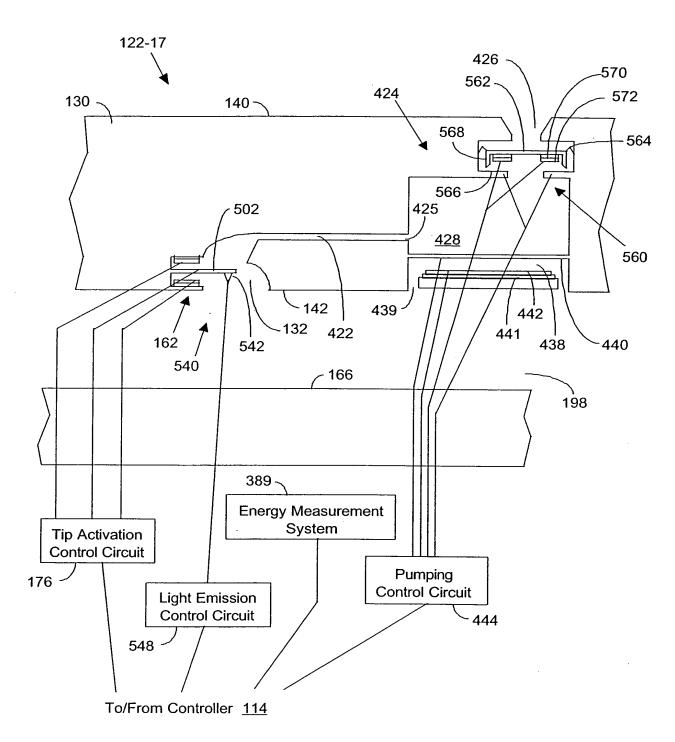


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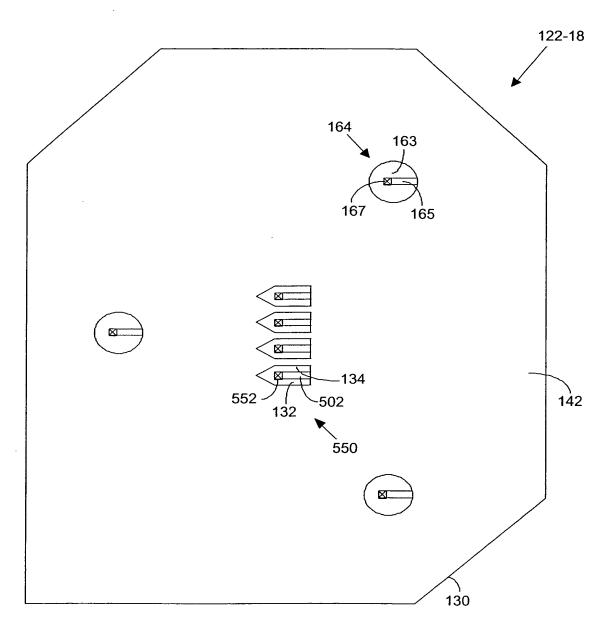


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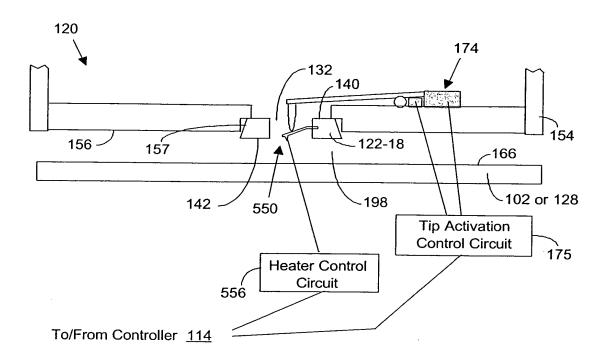


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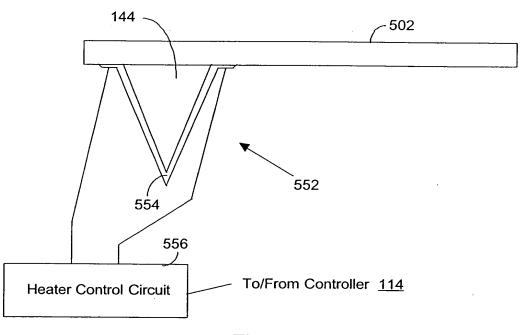


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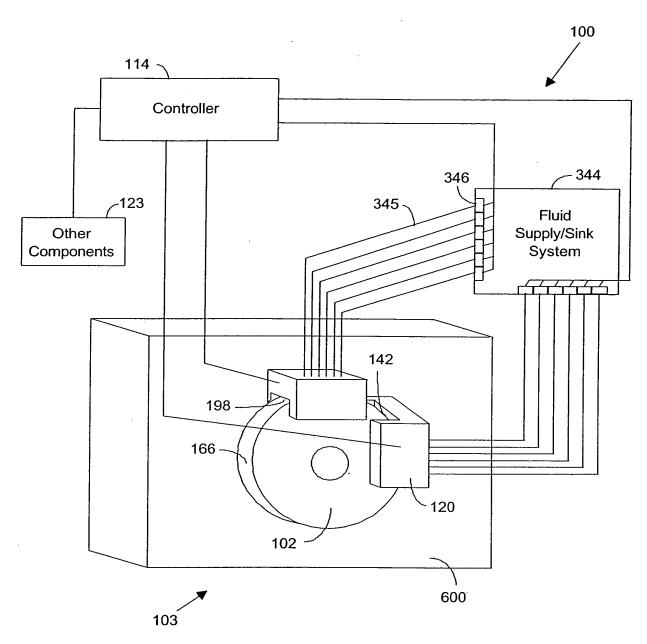


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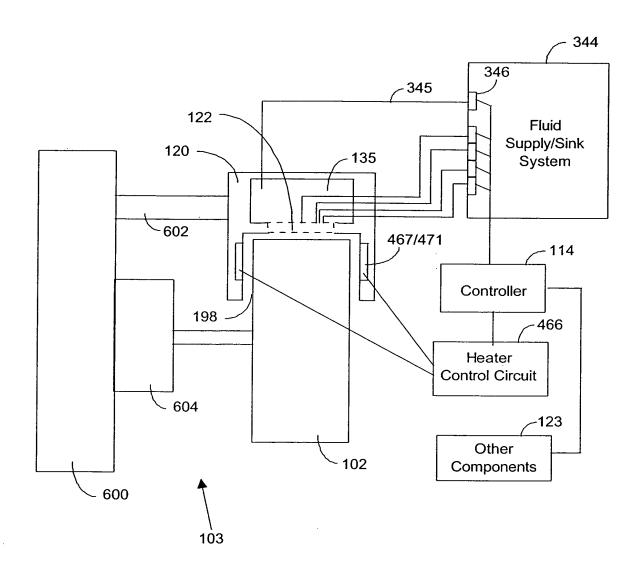


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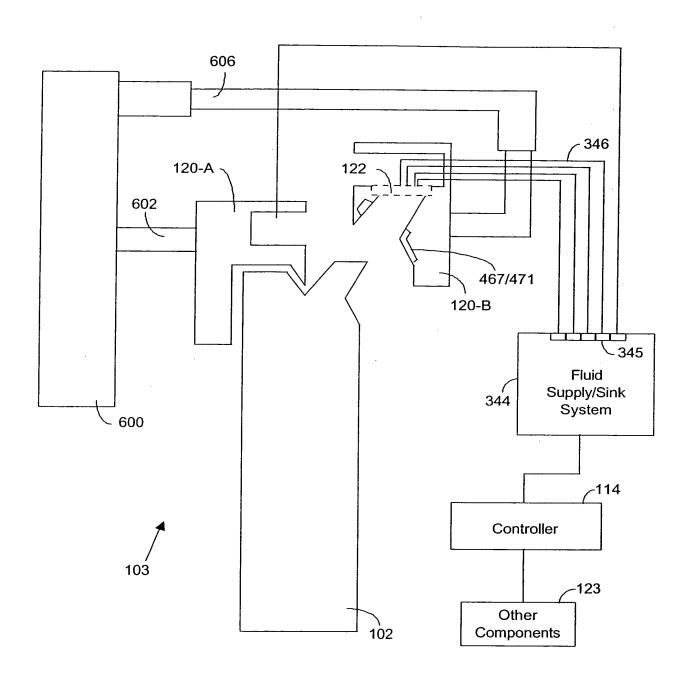


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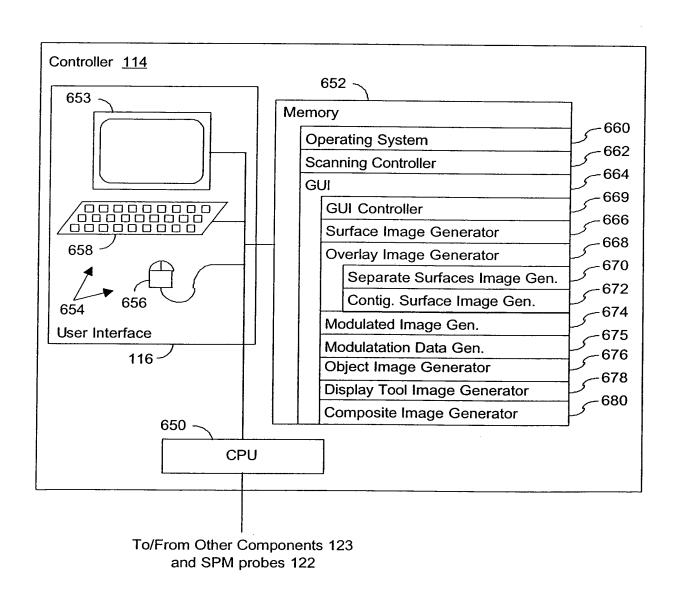


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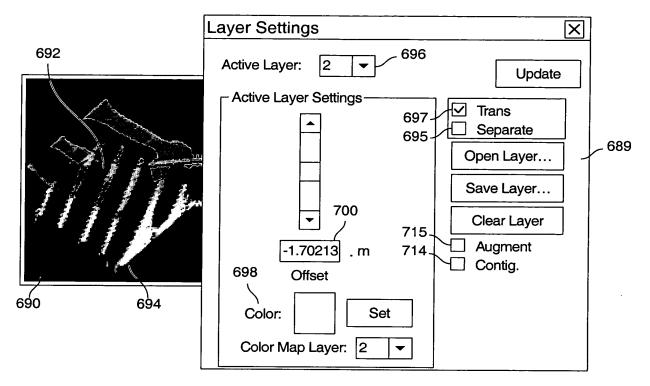


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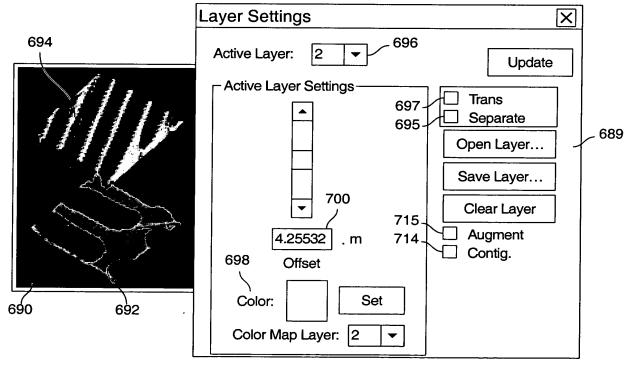


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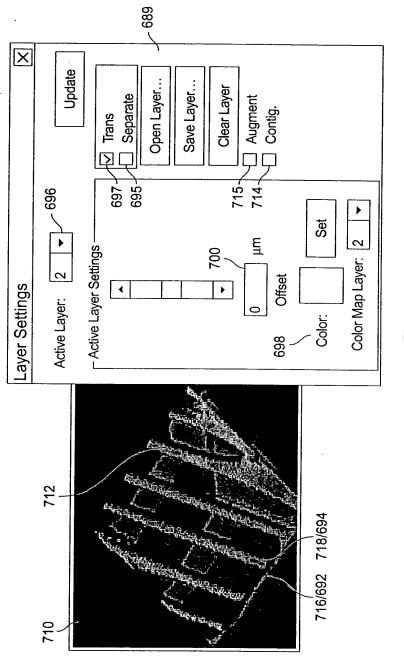


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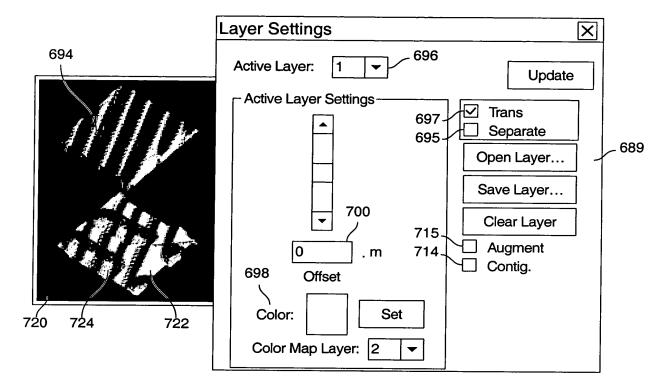


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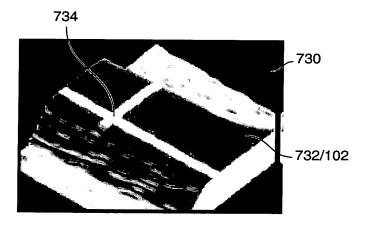


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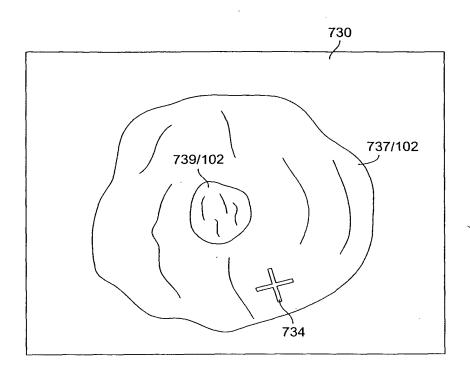


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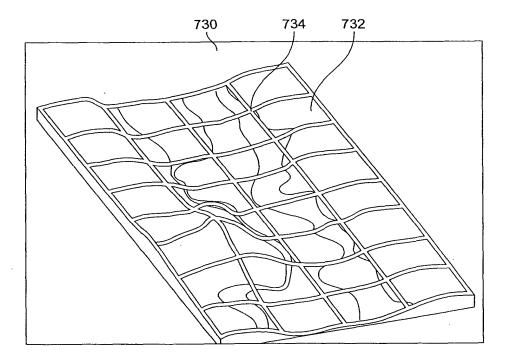


Figure 81

Title: Scanning Probe Microscopy Inspection and Modification System
Inventor: Victor B. Kley App. No. ______; Filed: _______
David N. Slone (650-326-2400) Docket No. 020921-001612US Page 53 of 55

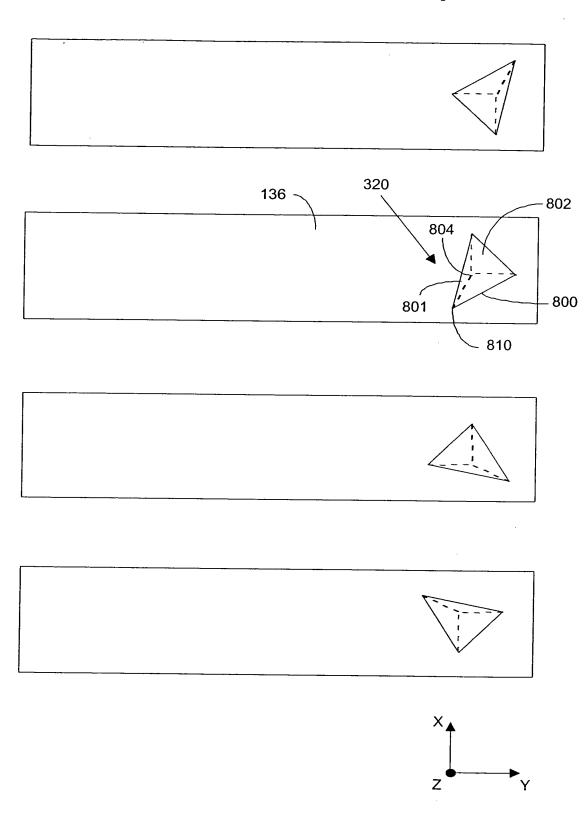


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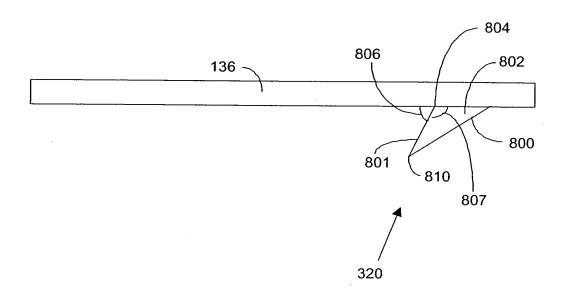


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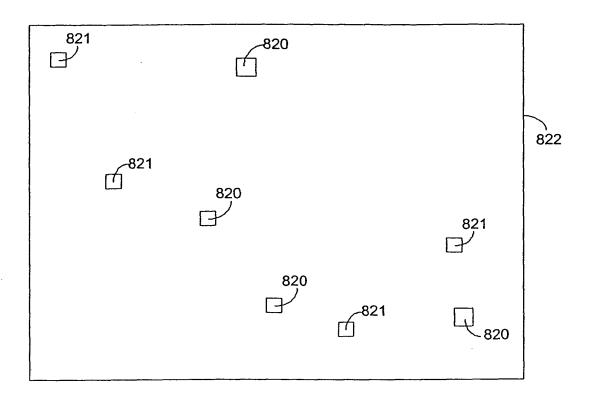


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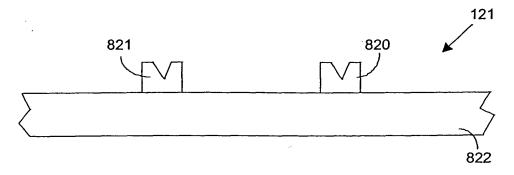


Figure 85